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A binary-counter-based test generator in compact testing systems

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Abstract

The use of the modified binary counter, as a test generator, is shown to allow to detect 100% of errors of the certain type in the combination scheme in the corresponding choice of the signature analyzer. If, as a result of reswitching, it is possible to apply signals from S counter minor digits to arbitrary S inputs of the programmable logic matrix then all the errors of multiplicity S and less in the column of the unit AND of the programmable logic matrix will be detected as a result of testing.
